

Notice of References Cited	Application/Control No. 10/786,005		Applicant(s)/Patent Under Reexamination IDE ET AL.	
	Examiner Edward F. Landrum		Art Unit 3724	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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	U	
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